

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination	
			10/807,318	LEE, WON HEE	
Examiner			Art Unit	3744	Page 1 of 1
Chen-Wen Jiang					

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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	K	US-			
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	M	US-			

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